

Sulfuric Acid 96%  
CMOS



Material No.: 9684-03  
Batch No.: 0000148559  
Manufactured Date: 2016/06/20  
Retest Date: 2021/06/19

## Certificate of Analysis

Test	Specification	Result
Assay (H <sub>2</sub> SO <sub>4</sub> )	95.0 – 97.0 %	96.3
Color (APHA)	<= 10	5
Residue after Ignition	<= 2 ppm	< 1
Chloride (Cl)	<= 0.1 ppm	< 0.1
Nitrate (NO <sub>3</sub> )	<= 0.2 ppm	< 0.1
Phosphate (PO <sub>4</sub> )	<= 0.3 ppm	< 0.1
Trace Impurities – Aluminum (Al)	<= 50.0 ppb	< 5.0
Arsenic and Antimony (as As)	<= 5 ppb	<0.1
Trace Impurities – Barium (Ba)	<= 10.0 ppb	< 1.0
Trace Impurities – Beryllium (Be)	<= 10.0 ppb	< 1.0
Trace Impurities – Bismuth (Bi)	<= 20.0 ppb	< 10.0
Trace Impurities – Boron (B)	<= 10.0 ppb	< 5.0
Trace Impurities – Cadmium (Cd)	<= 10.0 ppb	< 1.0
Trace Impurities – Calcium (Ca)	<= 50.0 ppb	2.0
Trace Impurities – Chromium (Cr)	<= 50.0 ppb	< 1.0
Trace Impurities – Cobalt (Co)	<= 10.0 ppb	< 1.0
Trace Impurities – Copper (Cu)	<= 10.0 ppb	< 1.0
Trace Impurities – Gallium (Ga)	<= 10.0 ppb	< 1.0
Trace Impurities – Germanium (Ge)	<= 10.0 ppb	< 10.0
Trace Impurities – Gold (Au)	<= 20.0 ppb	< 5.0
Heavy Metals (as Pb)	<= 200 ppb	< 50
Trace Impurities – Iron (Fe)	<= 100.0 ppb	1.0
Trace Impurities – Lead (Pb)	<= 20.0 ppb	< 1.0
Trace Impurities – Lithium (Li)	<= 10.0 ppb	< 1.0

Test	Specification	Result
Trace Impurities – Magnesium (Mg)	<= 50.0 ppb	< 1.0
Trace Impurities – Manganese (Mn)	<= 10.0 ppb	< 1.0
Trace Impurities – Mercury (Hg)	<= 5.0 ppb	< 0.1
Trace Impurities – Molybdenum (Mo)	<= 10.0 ppb	< 5.0
Trace Impurities – Nickel (Ni)	<= 10.0 ppb	< 5.0
Trace Impurities – Niobium (Nb)	<= 10.0 ppb	< 1.0
Trace Impurities – Potassium (K)	<= 50.0 ppb	< 10.0
Trace Impurities – Silicon (Si)	<= 50.0 ppb	< 10.0
Trace Impurities – Silver (Ag)	<= 10.0 ppb	< 1.0
Trace Impurities – Sodium (Na)	<= 100.0 ppb	< 5.0
Trace Impurities – Strontium (Sr)	<= 10.0 ppb	< 1.0
Trace Impurities – Tantalum (Ta)	<= 10.0 ppb	< 5.0
Trace Impurities – Thallium (Tl)	<= 20.0 ppb	< 5.0
Trace Impurities – Tin (Sn)	<= 50.0 ppb	< 10.0
Trace Impurities – Titanium (Ti)	<= 10.0 ppb	< 1.0
Trace Impurities – Vanadium (V)	<= 10.0 ppb	< 1.0
Trace Impurities – Zinc (Zn)	<= 50.0 ppb	< 1.0
Trace Impurities – Zirconium (Zr)	<= 10.0 ppb	< 1.0
Particle Count – 0.5 µm and greater	<= 60 par/ml	12
Particle Count – 1.0 µm and greater	<= 10 par/ml	1

For Microelectronic Use

Storage Conditions: Recommended Storage Conditions: 15° – 100°F  
Country of Origin: US  
Packaging Site: Phillipsburg Mfg Ctr & DC



Phillipsburg, NJ 9001:2008, 14001:2004, FSSC 22000  
Paris, KY 9001:2008  
Mexico City, Mexico 9001:2008  
Deventer, The Netherlands 9001:2008, 14001:2004, 13485:2003  
Gliwice, Poland 9001:2008, 13485:2012  
Selangor, Malaysia 9001:2008  
Dehradun, India, 9001:2008, 14001:2004, 13485:2003  
Mumbai, India, 9001:2008  
Panoli, India 9001:2008

*James Ethier*  
Jamie Ethier  
Vice President Global Quality